



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: W0804-01 Product Affected: IDT70V26, 70V261, 70V27, 70V9269, 70V9279 Date Effective: 25-Jul-2008	DATE: 25-Apr-2008	MEANS OF DISTINGUISHING CHANGED DEVICES: <input checked="" type="checkbox"/> Product Mark "W" Prefix on top mark or <input type="checkbox"/> Back Mark product name IDT70V26WL/S, <input type="checkbox"/> Date Code 70V261WL/S, 70V27WL/S, <input type="checkbox"/> Other 70V9269WL/S, 70V9279WL/S
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Contact: Dennis Lantz Title: Quality Engineer Phone #: (408) 284-4597 Fax #: (408) 284-1450 E-mail: Dennis.Lantz@idt.com	Attachment: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Samples: Available upon request
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DESCRIPTION AND PURPOSE OF CHANGE:

<input checked="" type="checkbox"/> Die Technology <input type="checkbox"/> Wafer Fabrication Process <input type="checkbox"/> Assembly Process <input type="checkbox"/> Equipment <input type="checkbox"/> Material <input type="checkbox"/> Testing <input type="checkbox"/> Manufacturing Site <input type="checkbox"/> Data Sheet <input type="checkbox"/> Other	<p>This notification is to advise our customers of the upgrade of process technology from CeMOS 9 to CeMOS 14 on IDT70V26, 70V261, 70V27, 70V9269 and 70V9279. There is no change to data sheet specifications.</p> <p>Attachment I details the qualification data for this change and Attachment II shows the affected list of part numbers.</p>
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RELIABILITY/QUALIFICATION SUMMARY:

There is no impact with regards to the package performance or reliability.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.

IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone # /Fax #: _____

CUSTOMER COMMENTS: _____

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



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ATTACHMENT I - PCN #: W0804-01

PCN Type: Process Technology Upgrade

Data Sheet Change: None

Detail of Change: This notification is to advise our customers of the upgrade of process technology from CeMOS 9 to CeMOS 14 on IDT70V26, 70V261, 70V27, 70V9269 and 70V9279. There is no change to data sheet specifications.

Table 1 as shown below depicts the comparizon between old and new process technology.

Description	Old	New
Die Revision	X	W
Wafer Fab	Fab 4	Fab 4
Fab Technology	CeMOS 9	CeMOS 14
# Poly Layers	3	1
# Metal Layers	2	6
Minimum Gate Length (μm)	0.35	0.13
Die Dimensions (mm^2)	52.4	11.7
Die Dimensions (Mil^2)	81.2K	18.2K

Note: All speed grades and package types are affected. Please refer to the ordering information given in the datasheet for specific part number.

Sample Availability: Now. Contact sales to request samples.



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PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT I - PCN #: W0804-01

Qualification Plan #: QSM-0502-01

Test Vehicle: 70V27W

Qualification Test Plan and Result:

Test Description	Test Method (Latest specs in effect)	Test Results SS / Rej
High Temperature Operating Life (Dynamic) (+125°C @ 1000 hours or equivalent)	JESD22-A108	116/0
Highly Accelerated Stress Test *(Biased, @ +130°C, +85%RH, 3 ATM, 100 hours)	JEDEC STD 22, Method A110	45/0
Autoclave *(2 ATM, Saturated steam @ +121°C, 168 hours)	EIA/JESD22-A102	45/0
Temperature Cycling *(-65°C to +150°C, 500 cycles)	JESD22-A104	45/0
High Temp Storage *(+150°C, 1000 hours)	JESD22-A103	77/0
ESD: Human Body Model @ 2000 Volts	MIL-STD 883 Method 3015	3/0
ESD: Charged Device Model @ 500 Volts	JEDEC 22-101	3/0
Latch-up (+ - I and V stress, + - 100mA Trigger)	EIA/JESD78	6/0

* Preconditioning per JESD22-A113B Level 3



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ATTACHMENT II - PCN #: W0804-01

Affected Part Number

IDT Part Number	IDT Part Number	IDT Part Number	IDT Part Number
70V27L15BF	70V27S35PF	70V26L35G	70V9279S9PRF
70V27L15PF	70V27S35PF8	70V26L35J	70V9279S9PRF8
70V27L15PF8	70V27S55PF	70V26L35J8	70V9279S7PRF
70V27L20PF	70V27S55PF8	70V26L55G	70V9279S7PRF8
70V27L20PF8	70V261L25PF	70V26L55J	70V9279S6PRF
70V27L25PF	70V261L25PF8	70V26L55J8	70V9279S6PRF8
70V27L25PF8	70V261L25PFI	70V26S25J	70V9269L12PRF
70V27L35PF	70V261L25PFI8	70V26S25J8	70V9269L12PRF8
70V27L35PF8	70V261L35PF	70V26S35G	70V9269L12PRFI
70V27L35PFI	70V261L35PF8	70V26S35J	70V9269L12PRFI8
70V27L35PFI8	70V261L55PF	70V26S35J8	70V9269L15PRF
70V27L55PF	70V261L55PF8	70V26S55G	70V9269L15PRF8
70V27L55PF8	70V261L25PFG	70V26S55J	70V9269L9PRF
70V27L20PFI	70V261L25PFG8	70V26S55J8	70V9269L9PRF8
70V27L20PFI8	70V261L25PFGI	70V9279L12PRF	70V9269S12PRF
70V27L15PFG	70V261L25PFGI8	70V9279L12PRF8	70V9269S12PRF8
70V27L20PFGI	70V261S25PF	70V9279L9PRF	70V9269S15PRF
70V27L20PFGI8	70V261S25PF8	70V9279L9PRF8	70V9269S15PRF8
70V27L15PFG8	70V261S35PF	70V9279L7PRF	70V9269S9PRF
70V27S15BF	70V261S35PF8	70V9279L7PRF8	70V9269S9PRF8
70V27S15PF	70V261S55PF	70V9279L7PRFI	70V9269S6PRF
70V27S15PF8	70V261S55PF8	70V9279L7PRFI8	70V9269S6PRF8
70V27S20PF	70V26L25J	70V9279L6PRF	70V9269S7PRFI
70V27S20PF8	70V26L25J8	70V9279L6PRF8	70V9269S7PRFI8
70V27S25PF	70V26L25JI	70V9279S12PRF	70V9269S7PRF
70V27S25PF8	70V26L25JI8	70V9279S12PRF8	70V9269S7PRF8